Abstracts

Unaccelerated reliability testing for T/R modules: need, methodology and supporting data

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MMIC temperature accelerated test data often does not capture many reliability degradation mechanisms present in transmit/receive (T/R) modules. Unaccelerated T/R module reliability testing can be used to help identify these mechanisms. This paper will identify several T/R module degradation mechanisms, a test methodology to obtain the maximum amount of information from unaccelerated test data, and supporting experimental data.

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